

| PRESENTATION TITLE | AUTHOR(S) | MORE |
|---|--|-----------------------------------|
| Pb free Challenges | <i>V. Goudarzi</i> | View Presentation |
| Microelectronic Packaging Materials Microelectronic Packaging Materials Development & Integration Development & Integration Challenges for Lead Free Challenges for Lead Free | <i>V. Wakharkar, and A. Dani</i> | View Presentation |
| The Mutual Impact of Lead-free Soldering and Fluxing Technology | <i>N.-C. Lee</i> | View Presentation |
| Sn-Whiskers: Truths and Myths | <i>J. Osenbach</i> | View Presentation |
| Deformation and Microstructural Evolution Processes in Lead-Free Sn-Ag Solder Joints due to Creep, Aging and Thermomechanical Fatigue and Preliminary Results on SAC Ball Grid Arrays | <i>T. R. Bieler, E. J. Cottis, L. P. Lehman, A. Zamiri and F. Pourboghart</i> | View Presentation |
| Manufacturing and Reliability of SnAgCu: Issues of "Backward" and "Forward" Compatibility | <i>C. Handwerker, K. Moon, U. Kattner, B. Boettinger, and M. Williams</i> | View Presentation |
| What the Electronics Industry Missed for 80 Years Interfacial Void Formation in Solder Joints with Cu Pad Structures during Thermal Aging | <i>D.W. Henderson, P. Borgesen, P. Kondos, I. De Sousa, L. Patry, and L. Yin</i> | View Presentation |
| Cross-Interaction between Cu and Ni in Lead-Free Solder Joints | <i>C.R. Kao</i> | View Presentation |
| Thermomechanical Fatigue and Fracture of Sn-based Solders | <i>K.N. Subramanian and A. Lee</i> | View Presentation |
| Panel Discussion Summary | <i>F. Hua</i> | View Presentation |